

Nanoscale Analysis of Conductance Switching Dynamics and Current Hysteresis in $(\text{GeTe})_2\text{-Sb}_2\text{Te}_3$ Superlattice Films Using Scanning Probe Methods

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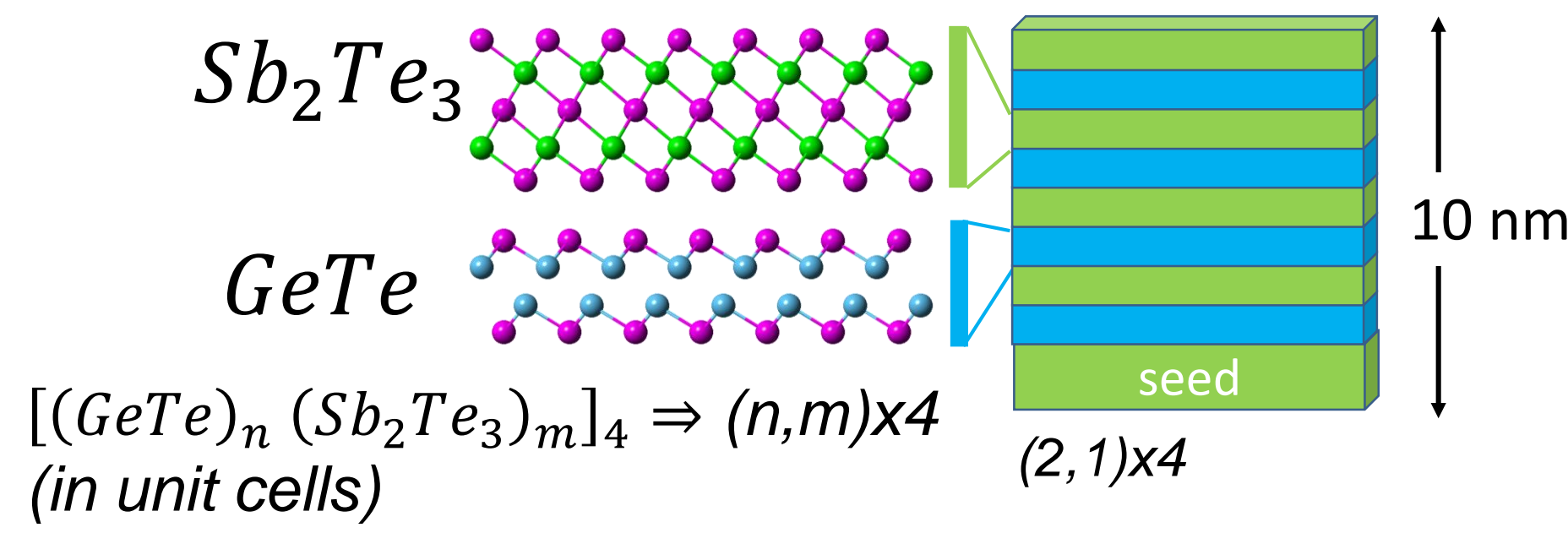
² CREST, Japan Science and Technology Agency, 4-1-8 Honcho, Kawaguchi, Saitama, 332-0012, Japan.

Motivation

Nanoscale evaluation of 2D phase change materials, i.e. chalcogenide superlattices made of *ferroelectric* GeTe and *topological insulator* Sb_2Te_3 layers, for use in phase-change memory, thermoelectric and magnetoelectric devices.

[Adv. Mater. Interfaces 1 (2014) 1300027]

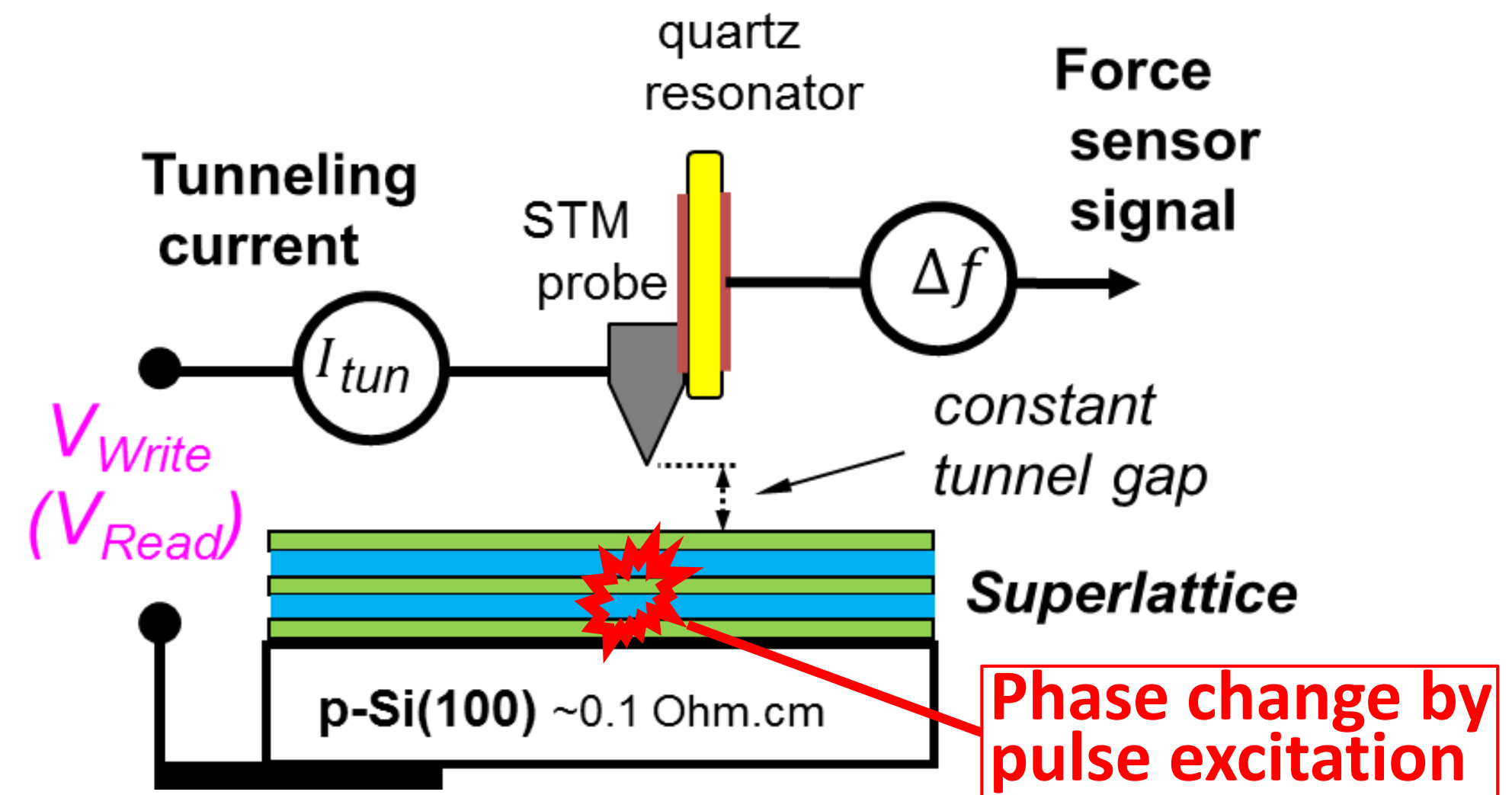
Superlattice (SL) structure



SL-A: seed layer and SL were deposited at 230°C.

SL-B: seed layer was grown at RT+annealing@230°C, and SL was deposited at 230°C.

Integrated STM/AFM system

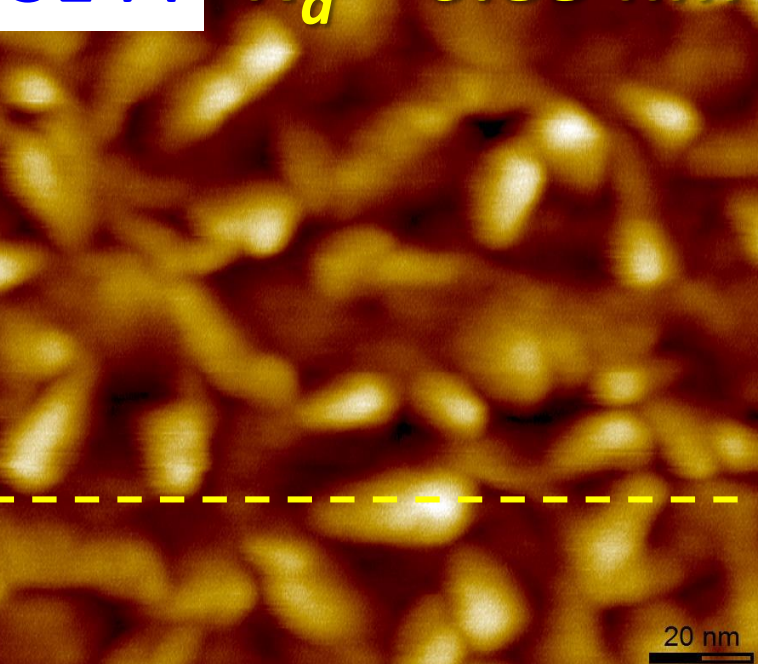


SL Film Structure

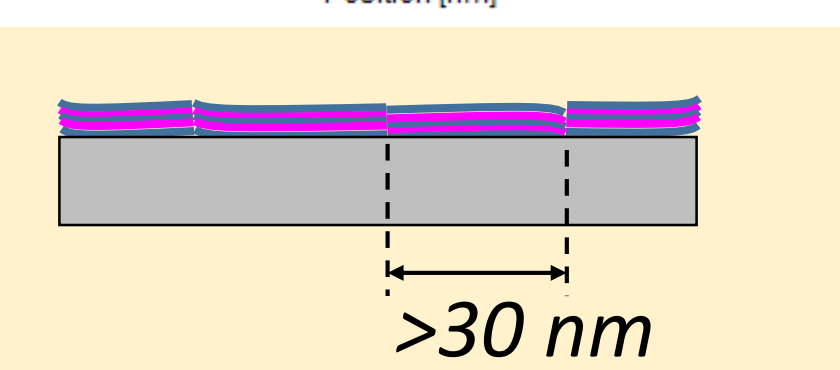
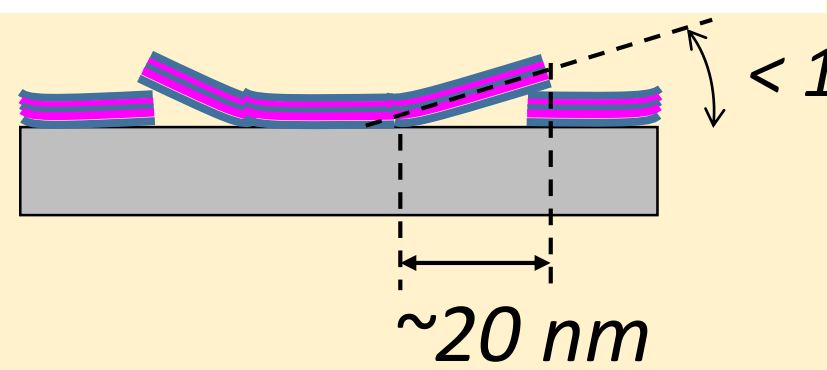
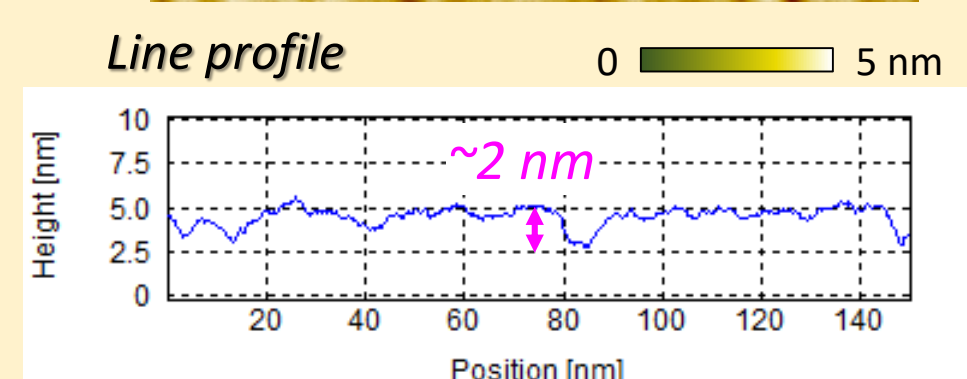
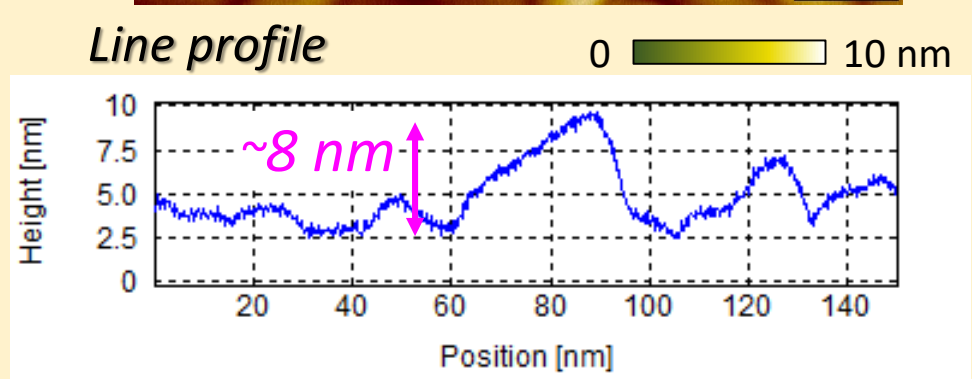
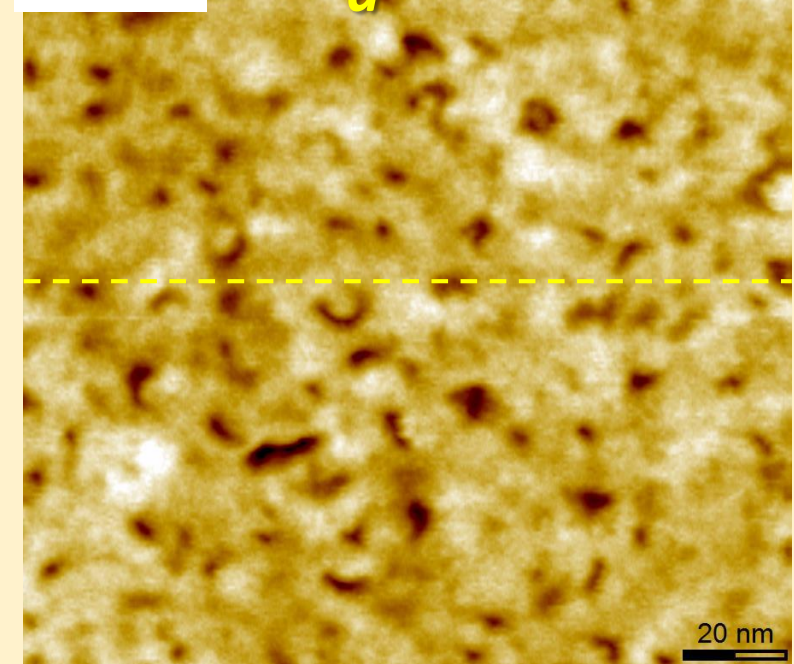
[Jpn.JAP 54, 04EK02 (2016)]

AFM

SL-A $R_a = 0.83 \text{ nm}$

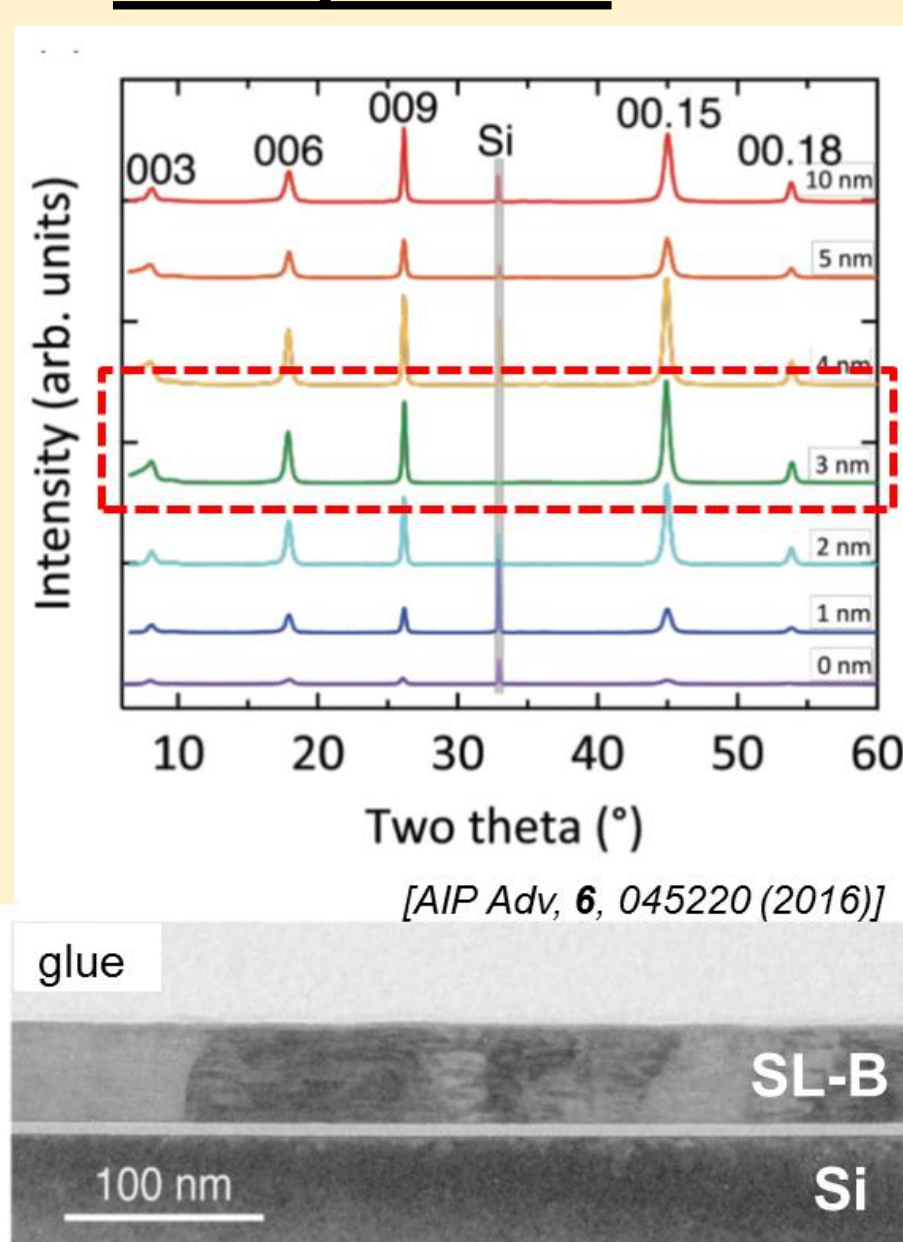


SL-B $R_a = 0.23 \text{ nm}$



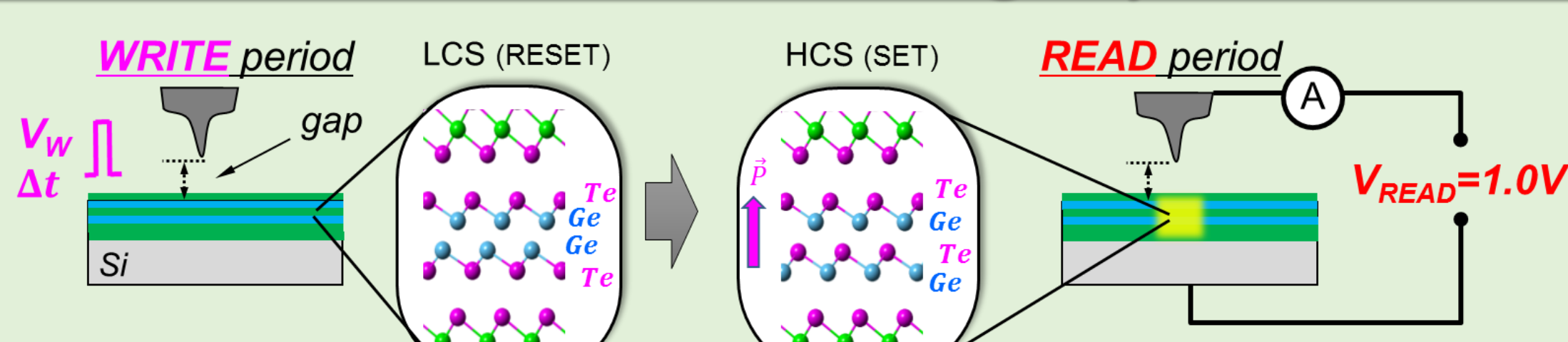
Initial transverse $R_{\perp} \sim 4.8 \text{ k}\Omega/\text{cm}^2$ (SL-A) and $\sim 4.2 \text{ k}\Omega/\text{cm}^2$ (SL-B)

XRD/TEM

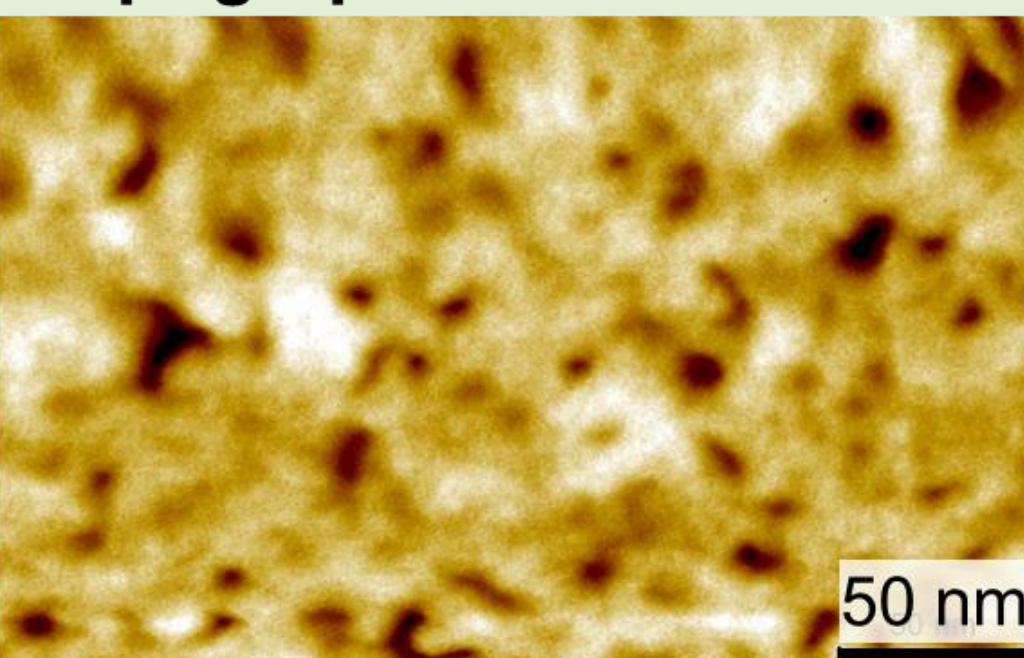


- Large grains size $\sim 30 \dots 100 \text{ nm}$
- Uniform crystal grain orientation

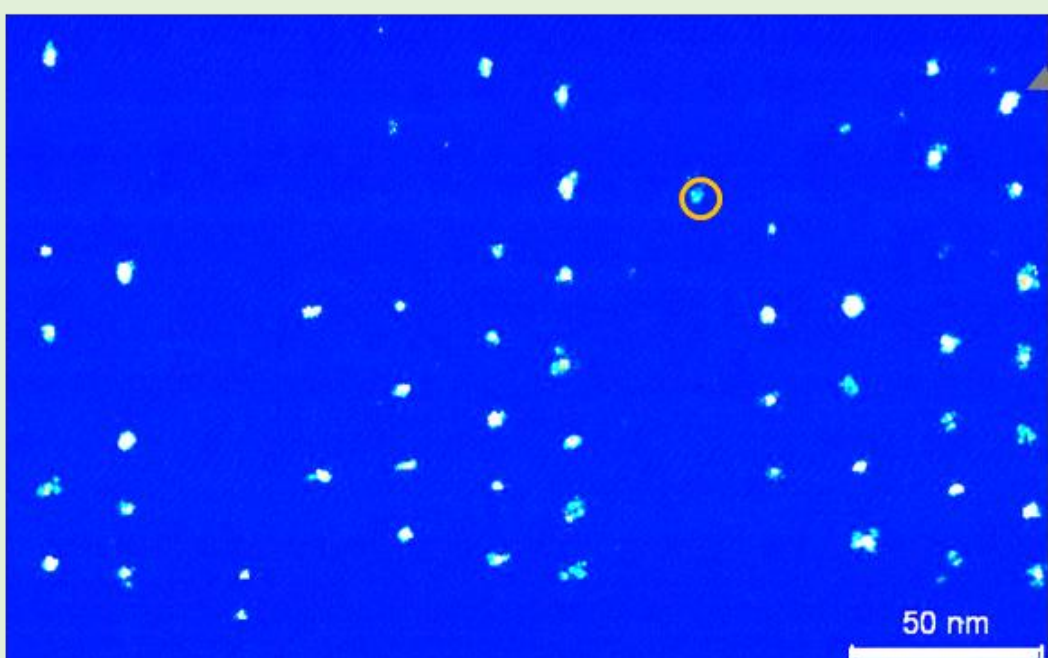
Conductance Switching by Pulse Voltage



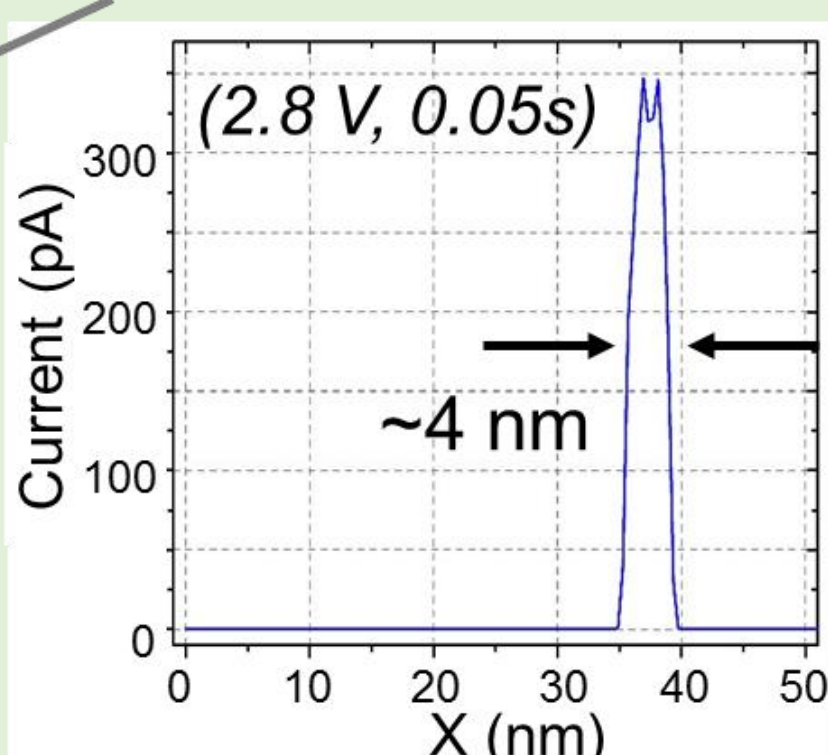
Topograph



READ map @1.0V



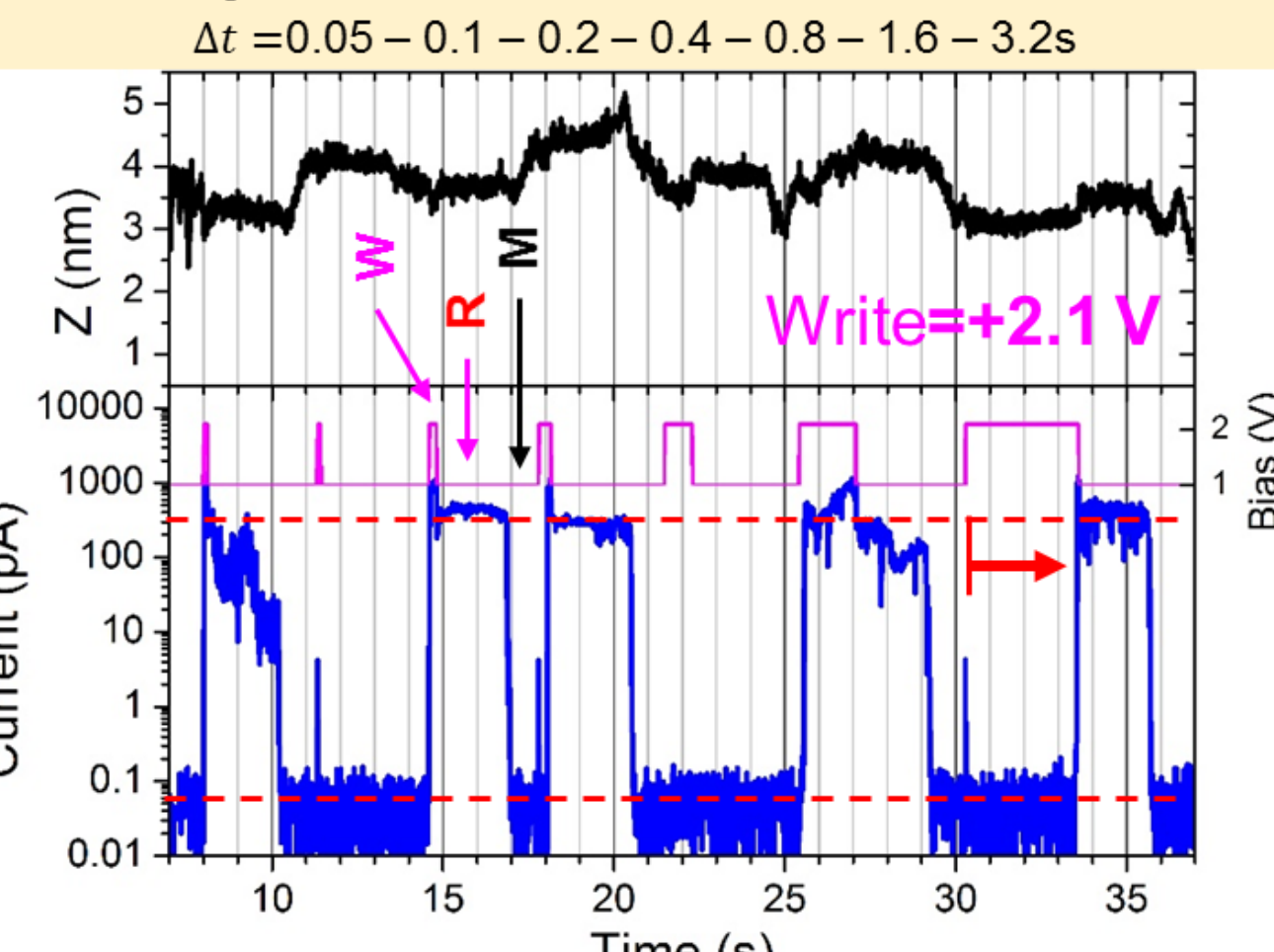
Single bit profile



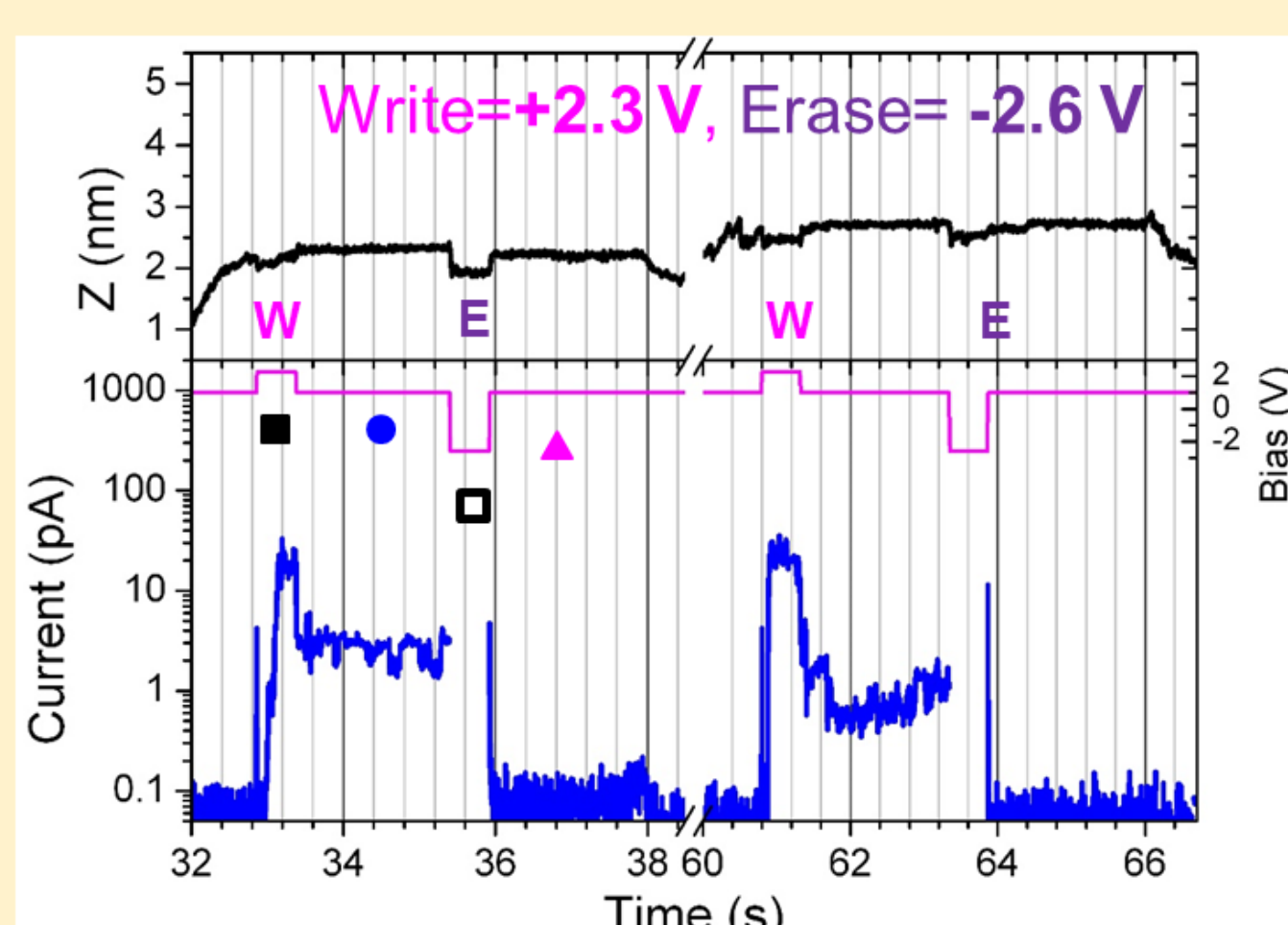
Morphology change $< 0.5 \text{ nm}$; OFF-ON current > 300 .

Conductance Switching Dynamics

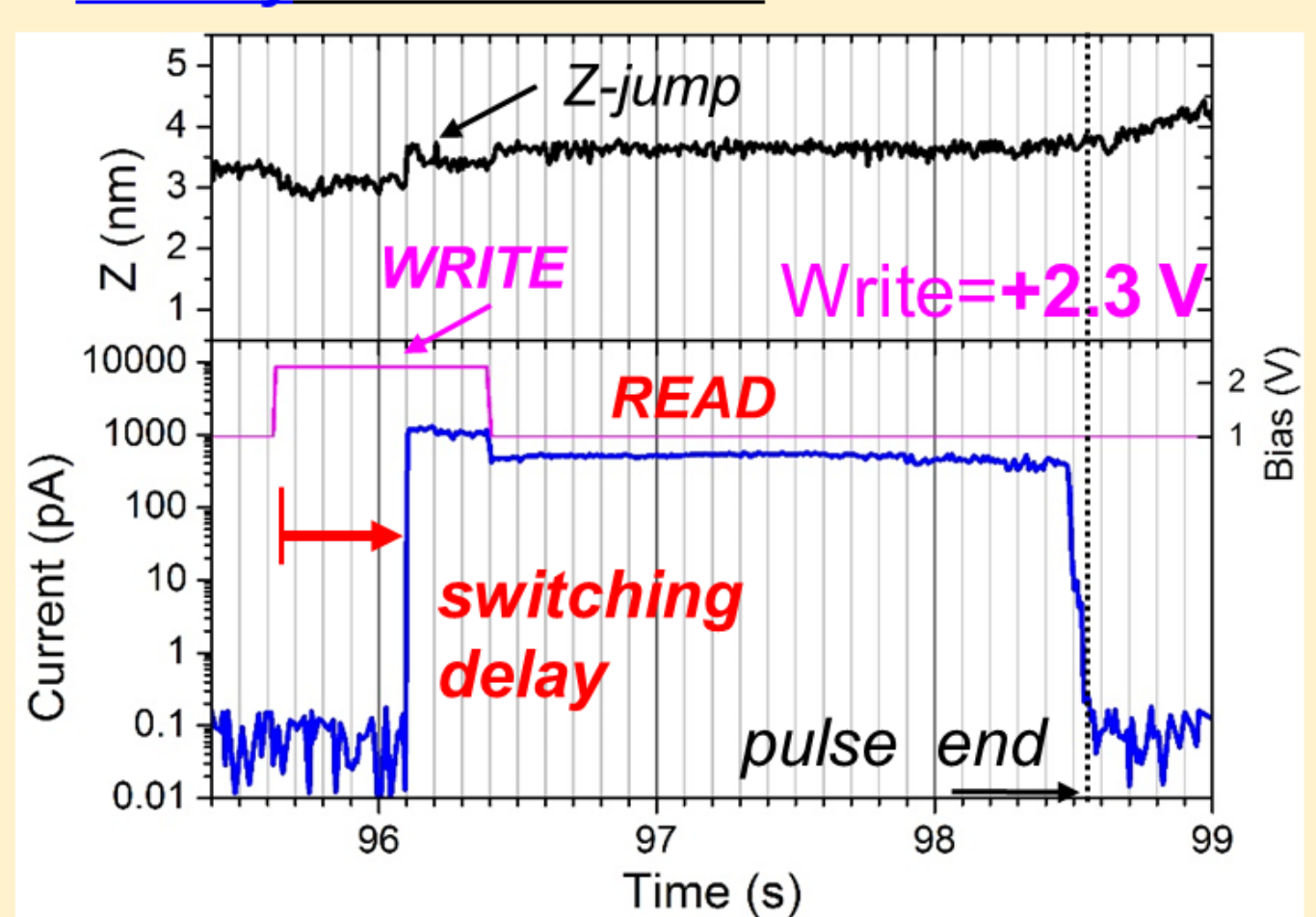
Pulse pattern: WRITE-READ



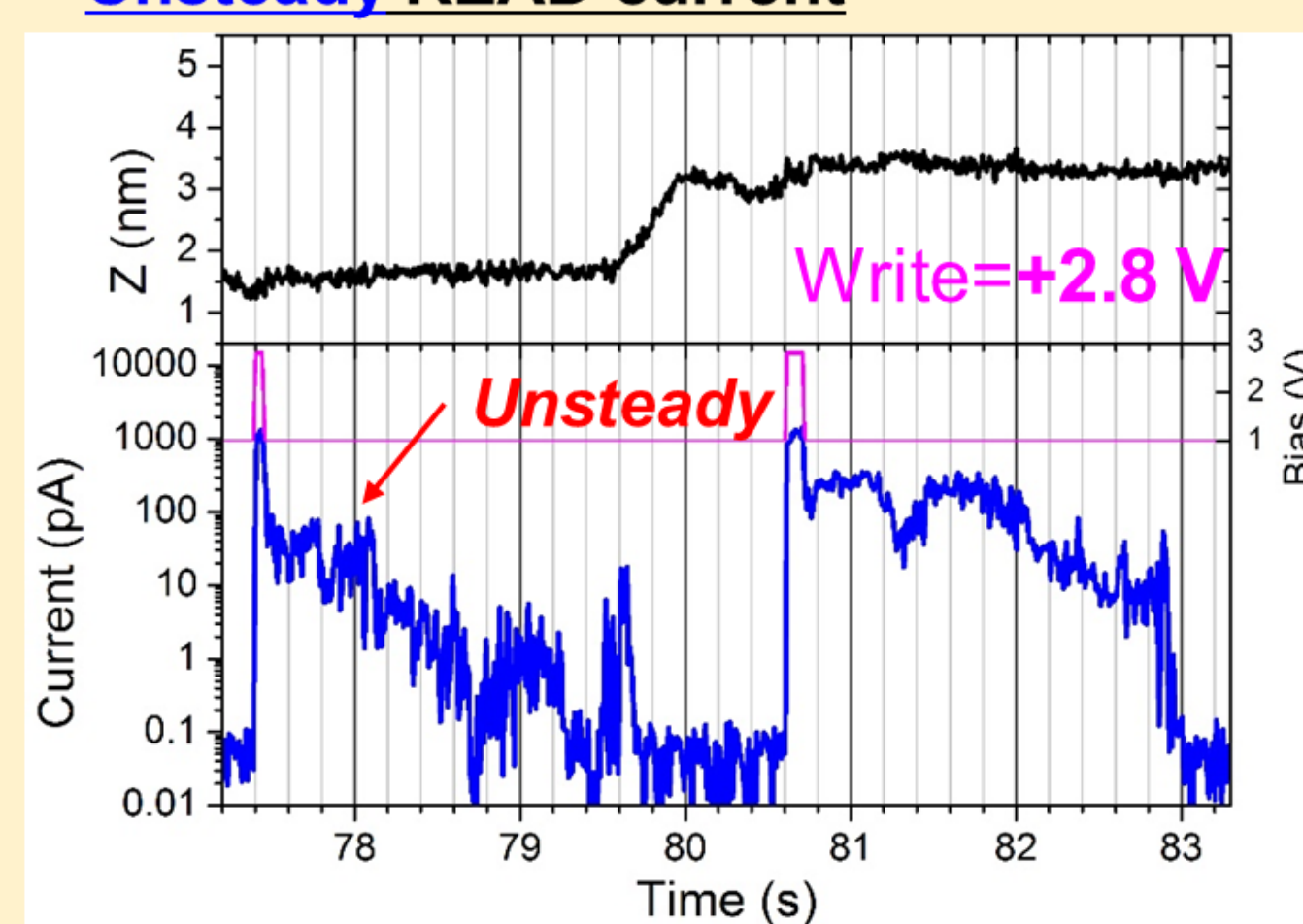
Pulse pattern: WRITE-READ-ERASE



Steady READ current



Unsteady READ current

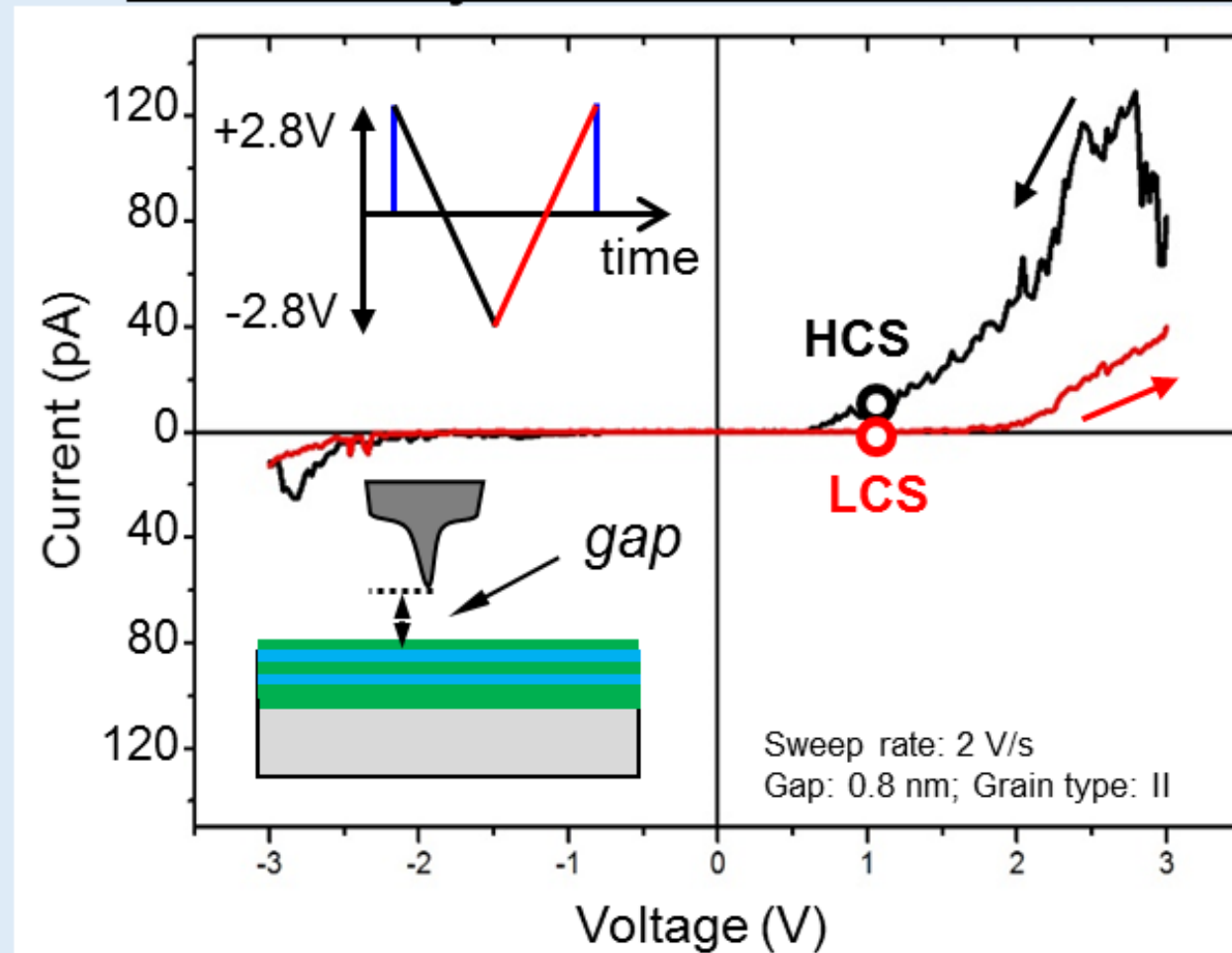


Key advantages :

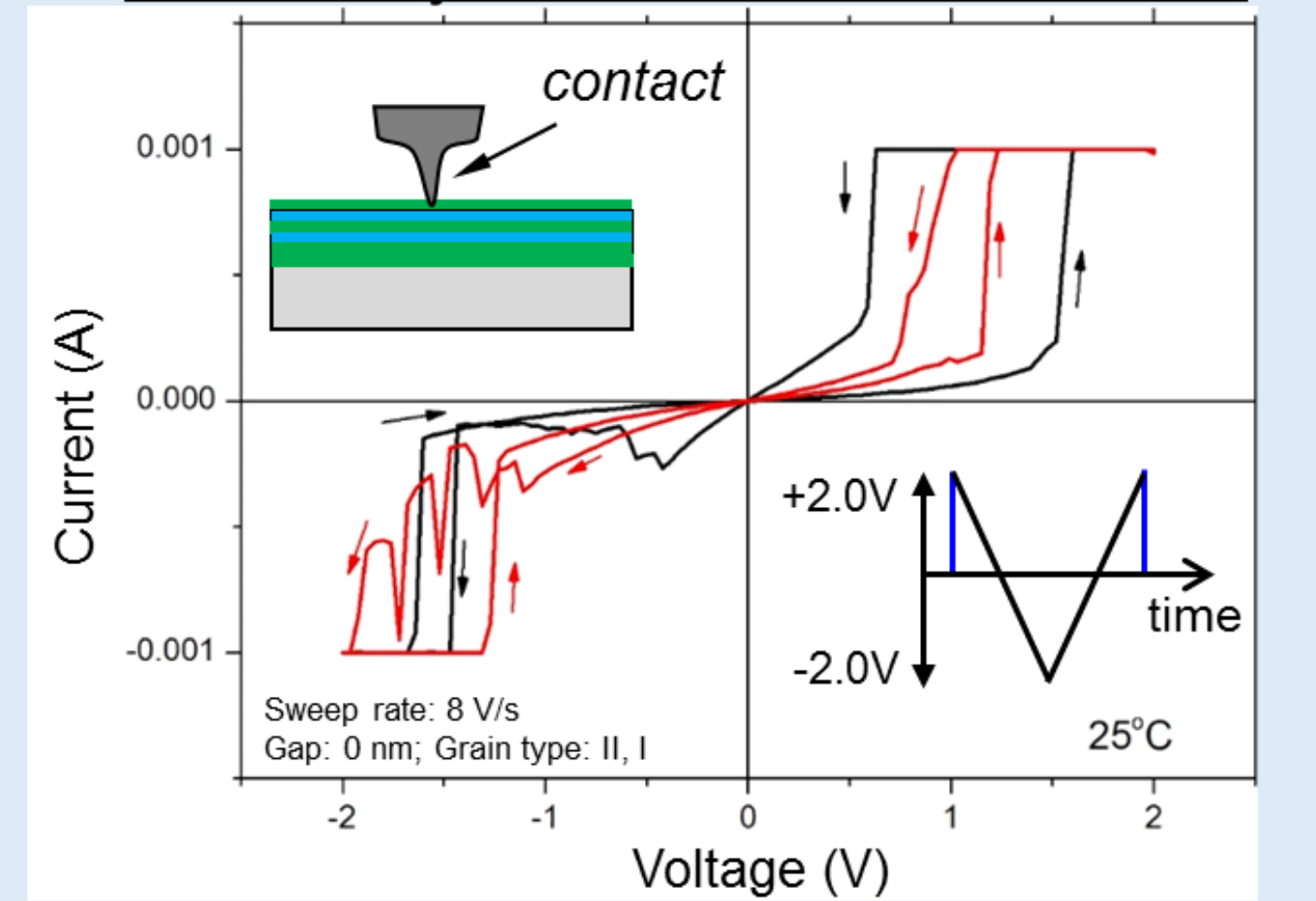
- Stress-free measurements in the non-contact mode,
- Easy tuning of electric field strength and injection current,
- Observe temporal change during the phase transition at nanoscale.

Current Hysteresis

Current hysteresis in SPM mode

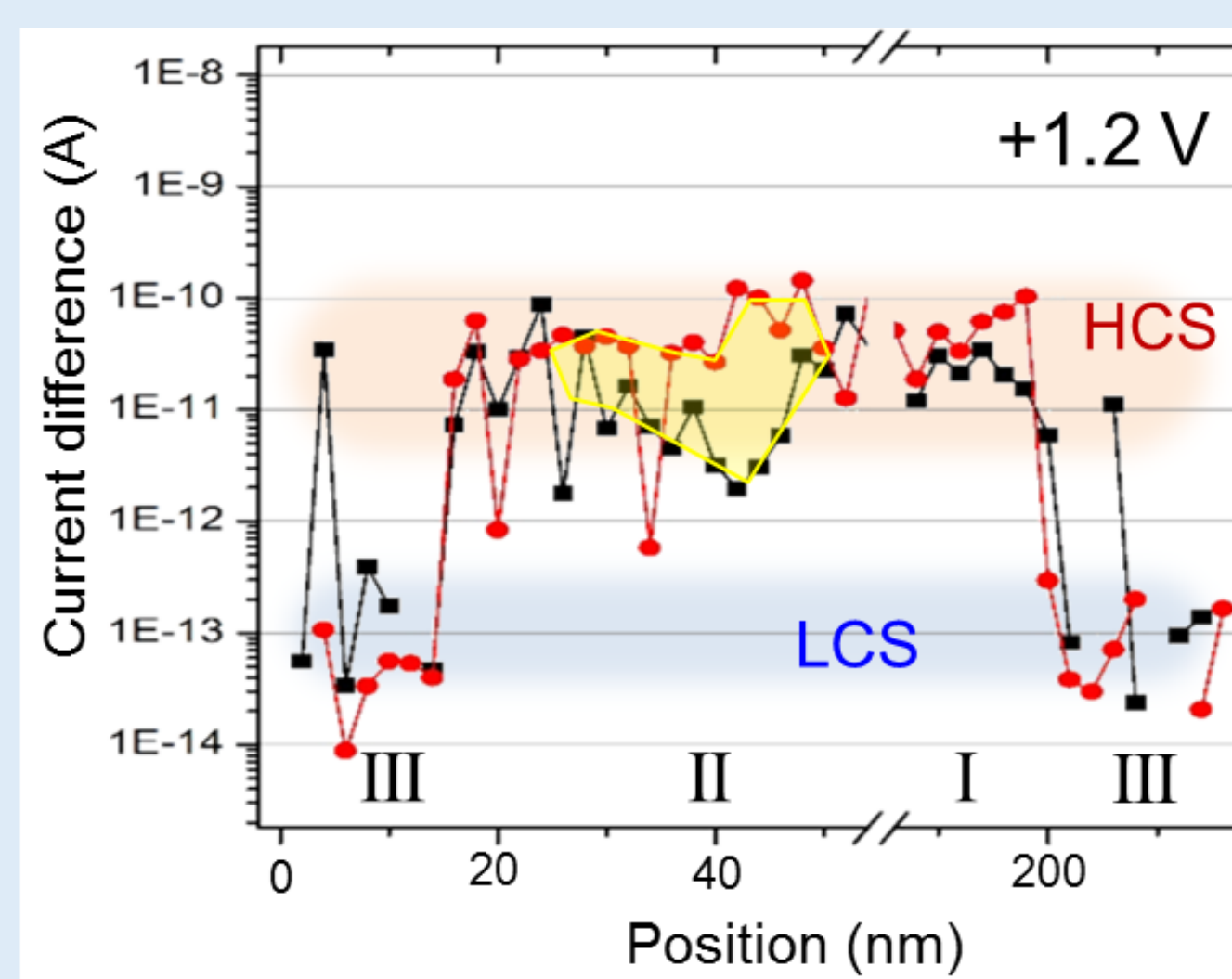


Current hysteresis in contact mode



Bipolar switching of the SL

Position-Dependence of the Hysteresis



Kinds of grain responses

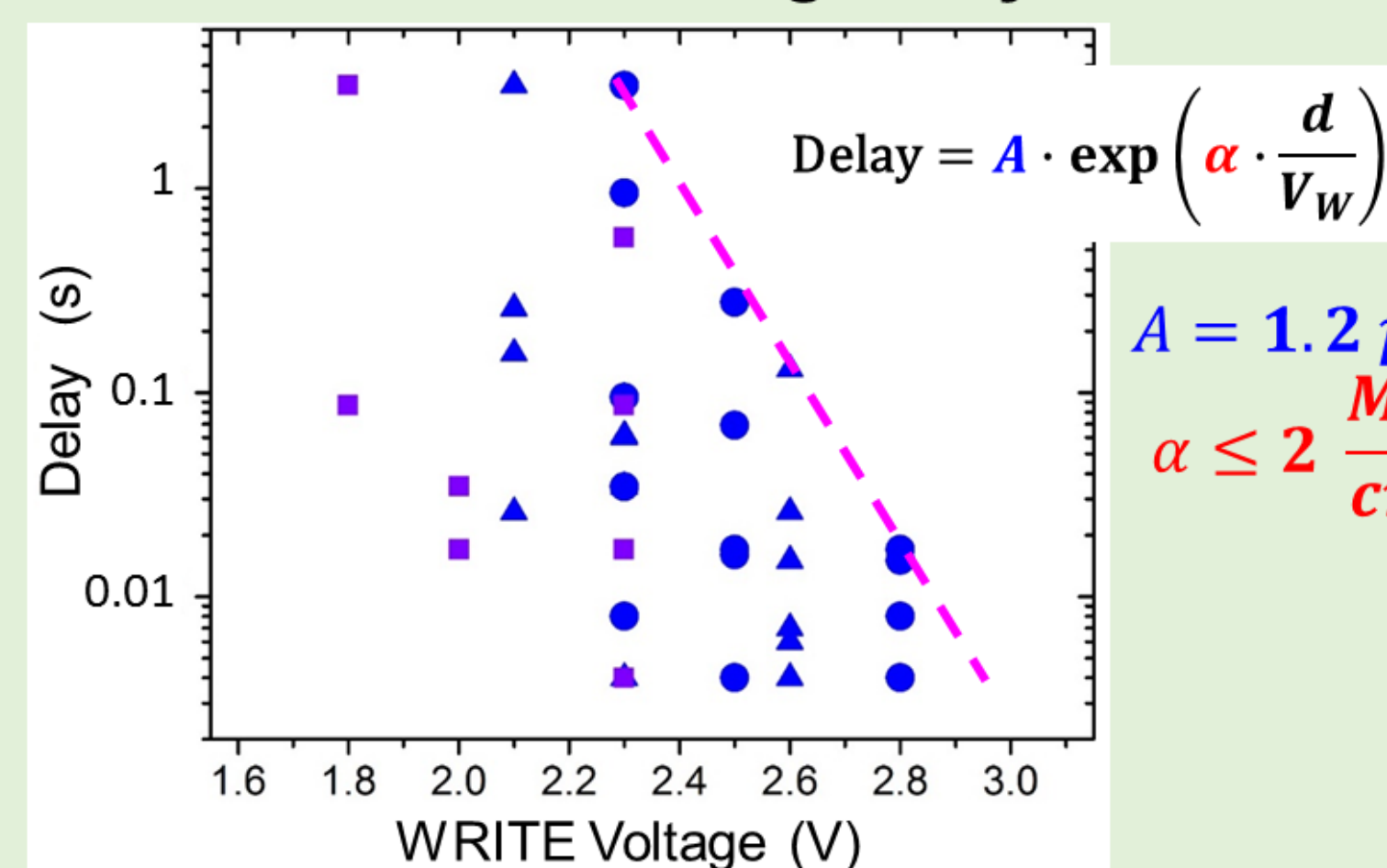
Type (%)	Switching (< 2.5V)	Switch Delay (s)	Hysteresis loop
I 52%	Yes	$< 10^{-3} *$	Yes
II 40%	Yes	0.05...3	Yes
III 8%	No	---	---

* - time resolution limit

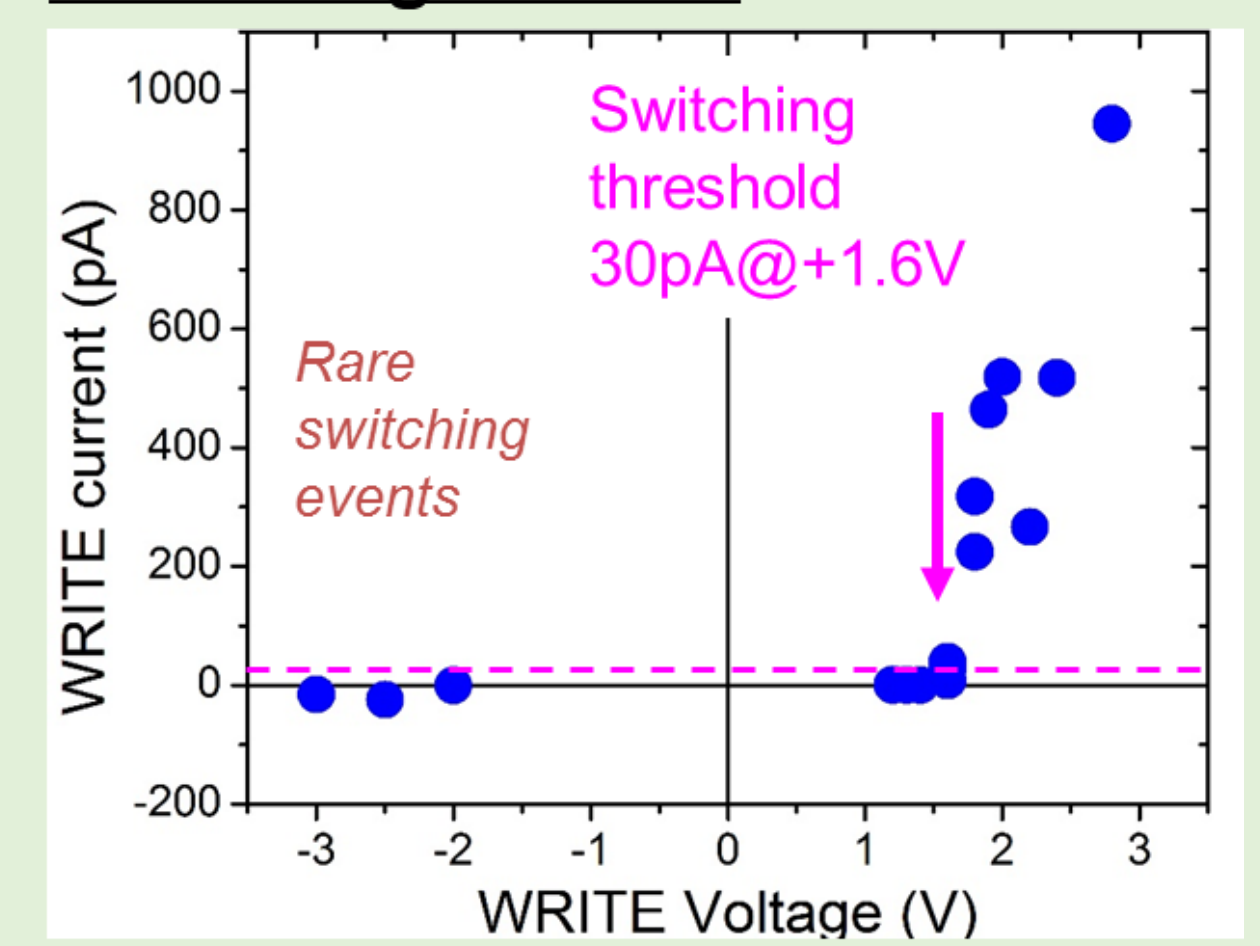
HCS/LCS ratio $\sim 10^2 - 10^3$

Statistics

Statistics of Switching Delay



Switching Current



Switching time $> 1.2 \text{ ps}$ @ 2MV/cm; WRITE current $> 30 \text{ pA}$

Summary

- We develop SPM-based analysis methods for evaluation of voltage-induced transformation in 2D systems at nanoscale.
- We applied them to examine the conductance switching in $(\text{GeTe})_2\text{-Sb}_2\text{Te}_3$ superlattice films.

[Sci. Reports 6, 33223 (2016)]